

FEE TRANSMITTAL for FY 2005

Patent fees are subject to annual revision.

Applicant claims small entity status. See 37 CFR 1.27

TOTAL AMOUNT OF PAYMENT

(\$)**380**

Complete if Known

Serial No.	10/748,827
Filing Date	December 29, 2003
First Inventor	Joonhyung Kwon
Examiner	Larkin, Daniel Sean
Art Unit	2856
Docket No.	PSI004-1C US

METHOD OF PAYMENT

☒ Check ☐ Credit Card ☐ Money Order ☐ Other ☐ None

☒ Deposit Account

Deposit
Account
Number

50-2263

Deposit
Account
Name

Silicon Valley Patent Group LLP

The Director is authorized to: (check all that apply)

☐ Charges fees(s) indicated below ☒ Credit any Overpayments

☒ Charges any additional fee(s) or any underpayment of fee(s)

☐ Charges fee(s) indicated below, except for the filing fee to the above-identified deposit account.

FEE CALCULATION

1. BASIC FILING FEE

Large Entity Fee		Small Entity Fee		Fee Description	Fee Paid
Code	(\$)	Code	(\$)		
1001	790	2001	395	Utility Filing Fee	
1002	350	2002	175	Design Filing Fee	
1003	550	2003	275	Plant Filing Fee	
1004	790	2004	395	Reissue Filing Fee	
1005	160	2005	80	Provisional Filing Fee	
SUBTOTAL (1)				(\$)	

2. EXTRA CLAIM FEES FOR UTILITY AND REISSUE

			Extra Claims		Fee from below		Fee Paid
Total Claims		13	-20**=	0	x	50	= 0
Independent Claims		4	-3**=	1	x	200	= 200
Multiple Dependent					x		=

Large Entity Fee		Small Entity Fee		Fee Description
Code	(\$)	Code	(\$)	
1202	50	2202	25	Claims in excess of 20
1201	200	2201	100	Independent claims in excess of 3
1203	360	2203	180	Multiple dependent claim, if not paid
1204	200	2204	100	** Reissue independent claims over original patent
1205	50	2205	25	** Reissue claims in excess of 20 and over original patent

SUBTOTAL (2) (\$)**200**

** or number previously paid if greater; For Reissues see above

FEE CALCULATION (continued)

3. ADDITIONAL FEES

Large Entity Fees		Small Entity Fees		Fee Description	Fees Paid
Code	(\$)	Code	(\$)		
1051	130	2051	65	Surcharge - late filing fee or oath	
1052	50	2052	25	Surcharge - late provisional filing fee or cover sheet	
1053	130	1053	130	Non-English specification	
1812	2,520	1812	2,520	For filing a request for <i>ex parte</i> reexamination	
1804	920*	1804	920*	Requesting publication of SIR prior to Examiner action	
1805	1,840*	1805	1,840*	Requesting publication of SIR after Examiner action	
1251	120	2251	60	Extension for reply within one month	
1252	450	2252	225	Extension for reply within second month	
1253	1020	2253	510	Extension for reply within third month	
1254	1,590	2254	795	Extension for reply within fourth month	
1255	2,160	2255	1,080	Extension for reply within fifth month	
1401	500	2401	250	Notice of Appeal	
1402	500	2402	250	Filing a brief in support of an appeal	
1403	1000	2403	500	Request for oral hearing	
1451	1,510	1451	1,510	Petition for a public use proceeding	
1452	500	2452	250	Petition to revive - unavoidable	
1453	1,500	2453	750	Petition to revive - unintentional	
1501	1,400	2501	700	Utility issue fee (or reissue)	
1502	130	2502	65	Design issue fee	
1503	160	2503	80	Plant issue fee	
1460	130	1460	130	Petitions to the Commissioner	
1807	50	1807	50	Processing fee for provisional applications	
1806	180	1806	180	Submission of Information Disclosure Statement	180
8021	40	8021	40	Recording each patent assignment per properties (times number of properties)	
1809	790	2809	395	Filing a submission after final rejection (37 CFR § 1.129(a))	
1810	790	2810	395	For each additional invention to be examined (37 CFR § 1.129(b))	
1801	790	2801	395	Request for Continued Examination (RCE)	
1802	900	1802	900	Request for expedited examination of a design application	

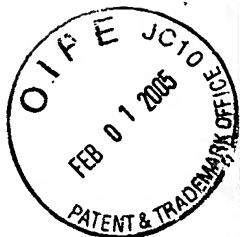
Other Fee (specify)

* Reduced by Basic Filing Fee Paid

SUBTOTAL (3) (\$)**180**

Submitted By

Name (Print/Type)	Omkar K. Suryadevara	Registration No. (Attorney/Agent)	36,320	Telephone	(408) 982-8203
Signature	<i>S. Omkar</i>	Date	February 1, 2005		



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: Joonhyung Kwon; Young Seok Kim; Sang-il Park
Assignee: PSIA Corporation
Title: Scanning Probe Microscope With Improved Probe Tip Mount
Serial No.: 10/748,827 Filing Date: December 29, 2003
Examiner: Larkin Group Art Unit: 2881
Docket No.: PSI004-1C US Confirmation No: 7166

Santa Clara, California
February 1, 2005

Mail Stop AMENDMENT
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02/08/2005 BABRAHA1 00000090 10748827
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**INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR §1.97(c)**

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, §1.97 and §1.98, the Applicants submit for consideration in the above-identified patent application the document listed on the accompanying Form PTO-1449. Copies of the cited journal articles are not attached because they were previously submitted in US Patent Application No. 10/077,835 from which the present patent application claims priority. The Examiner is requested to make these journal articles of record. The remaining references are not attached hereto, because these references are issued patents or publications which are readily available in the U.S. Patent and Trademark Office.

This Information Disclosure Statement is submitted pursuant to 37 CFR §1.97(c) as it is after receipt of a first Office Action on the merits but before mailing of a final Action or Notice of Allowance. Accordingly, a fee is required pursuant to 37 CFR §1.17(p). A Fee Transmittal form (PTO/SB/17) is attached to this submission.

In addition, Applicants submit for the Examiner's consideration, the prosecution histories of the following co-owned applications/patents, cited by serial number, first named inventor and filing date. The Applicants presume that the Examiner has access to and will review the cited applications/patents and the files thereof for any office actions,

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amendments or other materials that may be relevant to the patentability of the claims of the present application.

Citation of the following prosecution histories (including the arguments against patentability advanced by Examiners in their respective Office Actions and the Applicants' arguments in the corresponding Amendments) is in accordance with the case DAYCO PRODUCTS, INC. v. TOTAL CONTAINMENT, INC., 02-1497, decided May 23, 2003 by the Court of Appeals for the Federal Circuit. The Examiner is presumed to be knowledgeable about the current case law, including the above-mentioned Dayco case. However, if the Examiner needs a copy of the Dayco case, please call the undersigned.

For any of the following U.S. patent application(s) that are currently pending, the Applicants further presume that the Examiner will consider any future office actions, amendments or other materials in the file thereof that may be relevant to the patentability of the claims herein. **If the Applicants' understanding in this regard is not correct, please notify the undersigned so that copies of any such documents can be submitted to the Examiner.**

	Serial No.:	First Named Inventor	Filing Date:
1.	10/077,835	Jaewan Hong	Feb 15, 2002
2.	10/755,750	Joonhyung Kwon	Jan 12, 2004

Applicants would appreciate the Examiner initialing and returning the Form PTO-1449, indicating that the information has been considered and made of record herein.

The information contained in this Information Disclosure Statement is to the best of my knowledge and is not to be construed as a representation that: (i) a complete search has been made; (ii) additional information material to the examination of this application does not exist; (iii) the information, protocols, results and the like reported by third parties are accurate or enabling; or (iv) the above information constitutes prior art to the subject invention.

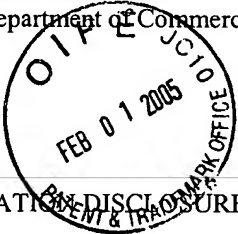
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Respectfully submitted,




Omkar K. Suryadevara
Attorney for Applicants
Reg. No. 36,320

U.S. Department of Commerce, Patent and Trademark Office  INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Application No.:	10/748,827
	Filing Date:	December 29, 2003
	First Named Inventor:	Joonhyung Kwon
	Group Art Unit:	2856
	Examiner Name:	Larkin, Daniel Sean
	Confirmation No.:	7166
	Attorney Docket No.:	PSI004-1C US

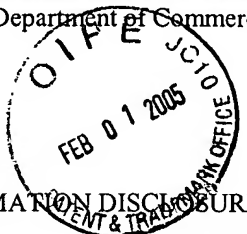
U.S. Patent Documents								
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
		US 5,672,816	09/1997	Park et al.	73	105		
		US 3,600,811	08/1971	Weyrauch, Adolf	33	707		
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AQ	Binnig G., et al, "Atomic Force Microscope", Physical Review Letters, vol 56, No. 9, Mar. 3, 1986 pp. 930-933.						
	AR	Hansma, P.K., et al, "A new optical-lever based atomic force microscope", J. Appl. Phys., 76(2) Jul. 15, 1994, American Institute of Physics, pp. 796-799.						
	AS	Meyer, Gerhard et al, "Erratum: Novel optical approach to atomic force microscopy", Appl. Phys. Lett. 53(24), Dec. 12, 1988, American Institute of Physics, pp. 2400-2402.						
	AT	"Dimensions 3100 Scanning Probe Microscope The Most Versatile SPM Ever Manufactured", www.di.com/Products/Dim/3100/D3100Main.html, Digital Instruments, Veeco Metrology Group © 1998-2001, print date Dec. 17, 2001, 4 pages.						
	AY	"Dimension 3100 Scan Techniques Unparalleled Power and Versatility", www.di.com/Products/Dim/3000/D31.scantechniques.html, Digital Instruments Veeco Metrology Group, ©1998-2001, print date Dec. 17, 2001, 2 pages.						
	AZ	AutoProbe M5™ Scanning Probe Microscope, Microscopes Veeco Metrology Group, 2001© TM Microscopes, Veeco, 4 pages.						
	BA	"TappingMode Imaging: Application and Technology", www.di.com/AppNotes/TapMode/TapModeMain.html, Digital Instruments, Veeco Metrology Group, ©1995-2001, Digital Instruments, print date Dec. 17, 2001, 5 pages.						
	BB	"NanoScope Vertical Engage Scanner", www.di.com/Products/Mult/JVScanner.html, Digital Instruments Veeco Metrology Group, ©1996-2001, Digital Instruments, print date Dec. 17, 2001, 1 page.						

Examiner:	Date Considered:
* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.	

U.S. Department of Commerce, Patent and Trademark Office  INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use several sheets if necessary)	Application No.:	10/748,827
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	Group Art Unit:	2856
	Examiner Name:	Larkin, Daniel Sean
	Confirmation No.:	7166
	Attorney Docket No.:	PSI004-1C US

U.S. Patent Documents								
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
		US 5,666,051	09/1997	Junker et al.	324	209		
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)								
	BC	"NanoScope MultiMode Scanning Probe Microscope", www.di.com/products/Multi/MMAIone.html, Digital Instruments Veeco Metrology Group, © 1996-2001, Digital Instruments, 8 page.						
	BD	"NanoScope ® MultiMode™ SPM The World's Highest Resolution SPM", www.di.com/Products/Multi/MMMain.html, Digital Instruments Veeco Metrology Group, ©1995-2001, Digital Instruments, print date Dec. 17, 2001 7 pages.						
	BI	"Products", Digital Instruments, Veeco Metrology Group Products, www.di.com/products2/products_all.html, print date Dec. 17, 2001, 5 pages.						
	BF	"AutoProbe CP Research The Most Flexible Research SPM", www.theermomicro.com/products/cp.htm, Microscopes Veeco Metrology Group, ©2001, print date Dec, 17, 2001, 2 pages.						
	BG	Manalis, S. R., et al, "High-speed atomic force microscopy using an integrated actuator and optical lever detection", Rev. Sci. Instrum. 67(9), Sep. 1996, pp. 3294-3297.						
	BH	"Microlevers™ General Purpose Cantilevers", Park Scientific Instruments © 1998, 1 page.						
	BI	Babcock, K.L. et al. "Phase Imaging: Beyond Topography", Digital Instruments, 3 pages, published prior to Feb. 15, 2002						
	BJ	"AutoProbe CP Research AP 2001", ThermoMicroscopes, 5 pages, published prior to Feb. 15, 2002						
	BK	"AutoProbe CP Research Scanning Probe Microscope", ThermoMicroscopes, 4 pages, published prior to Feb. 15, 2002						

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	Attorney Docket No.:	PSI004-1C US

U.S. Patent Documents								
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
		US 2001/0029674	10/2001	Cutler, Donald R.	33	1.00M		
Foreign Patent Documents								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)								
	BL	"AutoProbe M5E AP-5001", ThermoMicroscopes, 4 pages, published prior to Feb. 15, 2002						
	BM	"The Dimension TM 5000 Scanning Probe Microscope", Digital Instruments, 8 pages, published prior to Feb. 15, 2002						
	BN	"The Dimension TM 3000 Scanning Probe Microscope", Digital Instruments, 6 pages, published prior to Feb. 15, 2002						
	BO	"The Dimension TM 3100 Scanning Probe Microscope", Digital Instruments, 1 page, published prior to Feb. 15, 2002						

Examiner:	Date Considered:
* Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication with applicant.	